

Certificate of Analysis

Silicon Nitride, Amorphous

98.5+%, 15 - 30 nm (By SEM)

Country of Origin: USA

Stock #: 4750KE

Components	Contents (%)
Sif	<0.3
Cl	<0.25
O	<1.25

Analytical Techniques:

1. Gas-Volumetric Method
2. IR detector
3. Potential Measurement

Nanostructured & Amorphous Materials, Inc.

1526 Katy Gap Road, Suite# 302, Houston, TX 77494, USA

Phone: (281) 858-6571 • Fax: (281) 858-6507

E-mail: sales@nanoamor.com • Website: <http://www.nanoamor.com>